

CoolMOS[™] **Power Transistor**

Features

- Lowest figure-of-merit $R_{ON} x Q_g$
- Extreme dv/dt rated
- · High peak current capability
- Qualified according to JEDEC¹⁾ for target applications
- Pb-free lead plating; RoHS compliant
- · Ultra low gate charge

CoolMOS™ 900V is designed for:

- Quasi Resonant Flyback / Forward topologies
- PC Silverbox and consumer applications
- Industrial SMPS

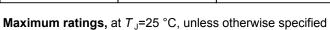
Product Summary

V _{DS} @ T _J =25°C	900	V
$R_{DS(on),max}$ @ T_J =25°C	1.2	Ω
Q _{g,typ}	28	nC

PG-TO220 FP



Туре	Package	Marking
IPA90R1K2C3	PG TO220 FP	9R1K2C



gate pin 1	drain pin 2 source pin 3
	pin 3

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current 2)	I _D	T _C =25 °C	5.1	А
		T _C =100 °C	3.2	
Pulsed drain current 3)	I _{D,pulse}	T _C =25 °C	10	1
Avalanche energy, single pulse	E _{AS}	I _D =0.92 A, V _{DD} =50 V	68	mJ
Avalanche energy, repetitive $t_{AR}^{(3),4)}$	E _{AR}	I _D =0.92 A, V _{DD} =50 V	0.31	1
Avalanche current, repetitive $t_{AR}^{3),4)}$	I _{AR}		0.92	А
MOSFET dv/dt ruggedness	dv/dt	V _{DS} =0400 V	50	V/ns
Gate source voltage	V_{GS}	static	±20	V
		AC (f>1 Hz)	±30	
Power dissipation	P _{tot}	T _C =25 °C	31	W
Operating and storage temperature	$T_{\rm J},T_{\rm stg}$		-55 150	°C
Mounting torque		M2.5 screws	50	Ncm



Maximum ratings, at T_J =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous diode forward current ²⁾	Is	<i>T</i> _C =25 °C	2.8	Α
Diode pulse current 3)	I _{S,pulse}		11	
Reverse diode dv/dt 5)	dv/dt		4	V/ns

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	

Thermal characteristics

Thermal resistance, junction - case	$R_{ m thJC}$		-	-	4.1	K/W
Thermal resistance, junction - ambient	R _{thJA}	leaded	1	-	62	
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	1.6 mm (0.063 in.) from case for 10 s	1	1	260	°C

Electrical characteristics, at T_J =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =250 μA	900	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}$, $I_{\rm D}=0.31~{\rm mA}$	2.5	3	3.5	
Zero gate voltage drain current	I _{DSS}	V _{DS} =900 V, V _{GS} =0 V, T _j =25 °C	1	1	1	μΑ
		V _{DS} =900 V, V _{GS} =0 V, T _j =150 °C	-	10	-	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =2.8 A, T _j =25 °C	1	0.94	1.2	Ω
		V _{GS} =10 V, I _D =2.8 A, T _j =150 °C	-	2.5	-	
Gate resistance	R _G	f=1 MHz, open drain	-	1.3	-	Ω



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	C iss	V _{GS} =0 V, V _{DS} =100 V,	-	710	-	pF
Output capacitance	C oss	f=1 MHz	-	35	-	
Effective output capacitance, energy related ⁶⁾	C _{o(er)}	V _{GS} =0 V, V _{DS} =0 V	-	23	-	
Effective output capacitance, time related 7)	C _{o(tr)}	to 500 V	-	86	-	
Turn-on delay time	t _{d(on)}	$V_{\rm DD}$ =400 V, $V_{\rm GS}$ =10 V, $I_{\rm D}$ =2.8 A, $R_{\rm G}$ =81.3 Ω	-	70	-	ns
Rise time	t _r		-	20	-	
Turn-off delay time	$t_{d(off)}$		-	400	-	
Fall time	t _f		1	40	-	
Gate Charge Characteristics						
Gate to source charge	Q _{gs}		-	3.2	-	nC
Gate to drain charge	Q_{gd}	V _{DD} =400 V, I _D =2.8 A,	-	12	-	
Gate charge total	Q _g	V _{GS} =0 to 10 V	-	28	tbd	
Gate plateau voltage	V _{plateau}		-	4.6	-	V
Reverse Diode						
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =2.8 A, T _j =25 °C	-	0.8	1.2	V
Reverse recovery time	t _{rr}		-	310	-	ns
Reverse recovery charge	Q _{rr}	V_R =400 V, I_F = I_S , di_F / dt =100 A/ μ s	-	3.7	-	μC
Peak reverse recovery current	I _{rrm}		-	19	-	Α

¹⁾ J-STD20 and JESD22

²⁾ Limited only by maximum temperature

³⁾ Pulse width t_p limited by $T_{J,max}$

⁴⁾ Repetitive avalanche causes additional power losses that can be calculated as $P_{AV} = E_{AR} * f$.

 $^{^{5)}} I_{SD} \!\! \leq \!\! I_D, \text{di/dt} \!\! \leq \!\! 200 \text{A/} \mu \text{s}, V_{DClink} \!\! = \!\! 400 \text{V}, V_{peak} \!\! < \!\! V_{(BR)DSS}, T_J \!\! < \!\! T_{J,max}, \text{identical low side and high side switch}$

 $^{^{6)}}$ $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 50% V_{DSS} .

 $^{^{7)}}$ C_{o(tr)} is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 50% V_{DSS} .



1 Power dissipation

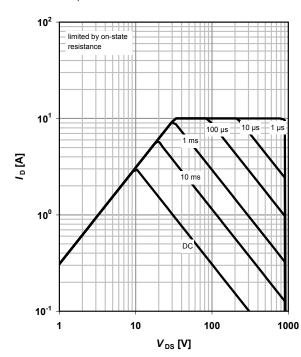
$$P_{\text{tot}}$$
=f(T_{C})

40 30 10 0 0 25 50 75 100 125 150 T_C [°C]

2 Safe operating area

$$I_D$$
=f(V_{DS}); T_C =25 °C; D =0

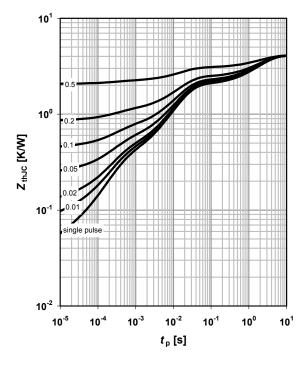
parameter: t_p



3 Max. transient thermal impedance

 Z_{thJC} = $f(t_P)$

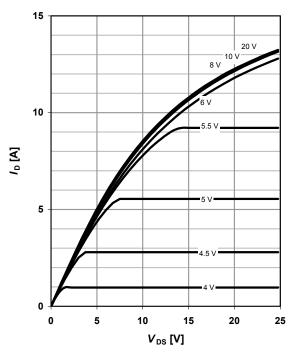
parameter: $D=t_p/T$



4 Typ. output characteristics

 I_D =f(V_{DS}); T_J =25 °C

parameter: V_{GS}





5 Typ. output characteristics

 I_D =f(V_{DS}); T_J =150 °C

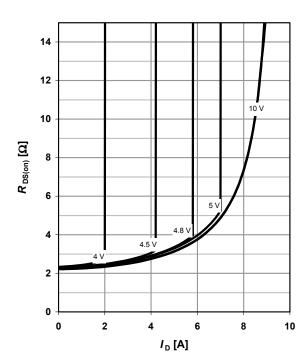
parameter: $V_{\rm GS}$

7 6 8V 10V 5 4 4-5V 4 10 0 5 10 15 20 4 4V 10 10 15 20 25 V_{DS} [V]

6 Typ. drain-source on-state resistance

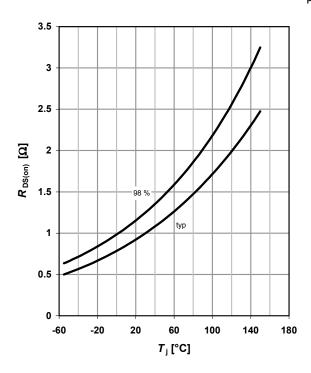
 $R_{DS(on)}$ =f(I_D); T_J =150 °C

parameter: V_{GS}



7 Drain-source on-state resistance

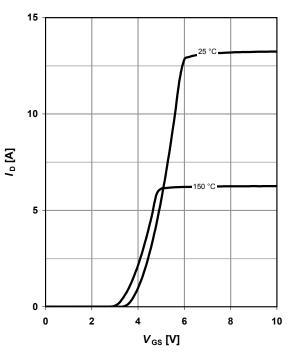
 $R_{DS(on)} = f(T_i); I_D = 2.8 \text{ A}; V_{GS} = 10 \text{ V}$



8 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 20V$

parameter: $T_{\rm j}$





9 Typ. gate charge

 V_{GS} =f(Q_{gate}); I_D =2.8 A pulsed

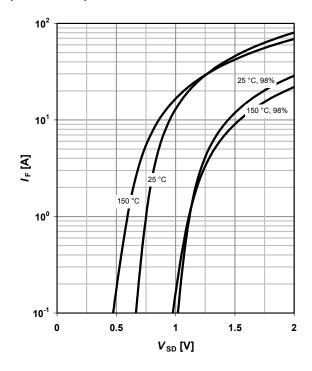
parameter: $V_{\rm DD}$

8 4 400 V 720 V 720 V 720 V 720 V Q gate [nC]

10 Forward characteristics of reverse diode

 $I_F = f(V_{SD})$

parameter: T_J

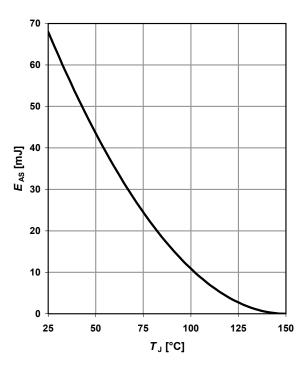


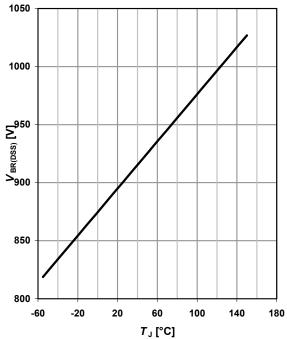
11 Avalanche energy

 E_{AS} =f(T_J); I_D =0.92 A; V_{DD} =50 V

12 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f(T_J); I_D =0.25 mA





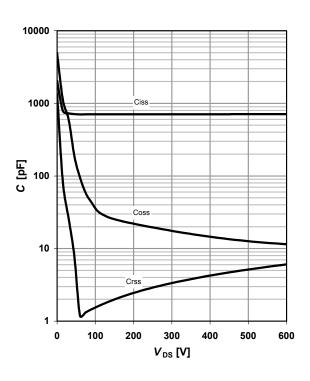


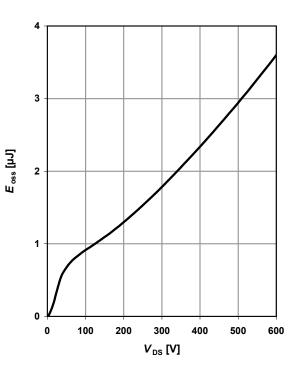
13 Typ. capacitances

$C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$

14 Typ. C_{oss} stored energy

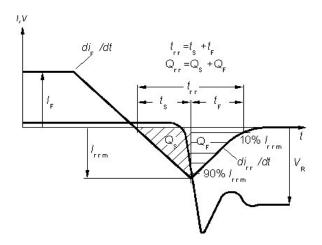
$$E_{oss} = f(V_{DS})$$





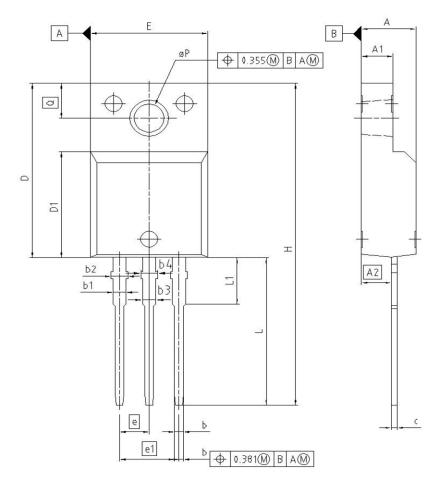


Definition of diode switching characteristics

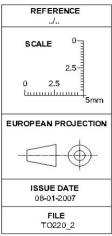




PG-TO220 FP Outline/Fully isolated package (2500VAC; 1minute)



DIM	MILLIN	TETERS	INCI	HES
DIM	MIN	MAX	MIN	MAX
A	4.55	4.85	0.179	0.191
A1	2.55	2.85	0.100	0.112
A2	2.42	2.72	0.095	0.107
b	0.65	0.85	0.026	0.033
b1	0.95	1.33	0.037	0.052
b2	0.95	1.51	0.037	0.059
b3	0.65	1.33	0.026	0.052
b4	0.65	1.51	0.026	0.059
C	0.40	0.63	0.016	0.025
D	15.85	16.15	0.624	0.636
D1	9.53	9.83	0.375	0.387
E	10.35	10.65	0.407	0.419
e	2.	54	0.1	100
e1	5.	08	0.2	200
N		3		3
н	29.45	29.75	1.159	1.171
L	13.45	13.75	0.530	0.541
L1	3.15	3.45	0.124	0.136
pΡ	2.95	3.20	0.116	0.126
Q	3.15	3.50	0.124	0.138



Dimensions in mm/inches



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